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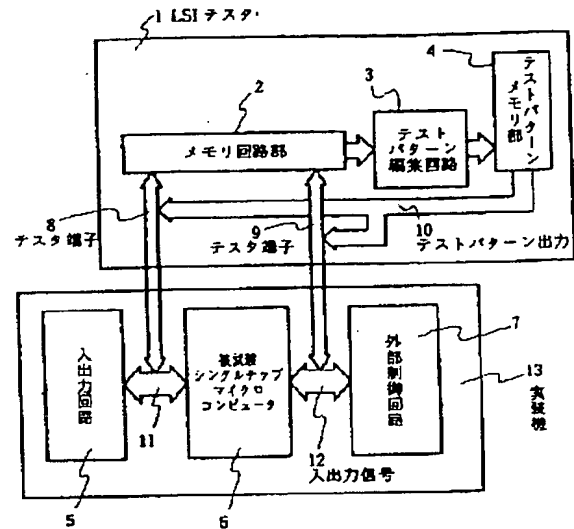
APPLICATION DATE : 18-10-90
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TITLE : LSI TESTER



ABSTRACT : PURPOSE: To enable a test closer to a condition of a customer's use by creating operation on a machine which packages a single-chip microcomputer to be tested and then achieving with an LSI tester.

CONSTITUTION: A single-chip microcomputer to be tested 6 is connected by an I/O circuit 5 and an external control circuit 7 and then single-chip microcomputer I/O signals 11 and 12 on a packaging machine 13. Also, the I/O signals 11 and 12 of the single-chip microcomputer and tester terminals 8 and 7 are connected and then the single-chip microcomputer 6 allows a signal during operation to be inputted to a memory circuit part 2 by a built-in program. Information which is inputted to a memory circuit 2 is edited to a test pattern through a test pattern editing circuit 3 and is stored into a memory part 4, thus enabling operation test to be performed according to test pattern information of the memory part 4.

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